

LOW-POWER DUAL 2-INPUT POSITIVE-AND GATE

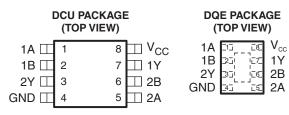
Check for Samples: SN74AUP2G08

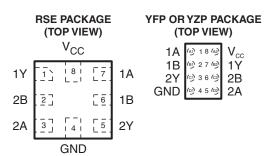
FEATURES

- Available in the Texas Instruments NanoStar™ Package
- Low Static-Power Consumption (I_{CC} = 0.9 μA Max)
- Low Dynamic-Power Consumption (C_{pd} = 4.3 pF Typ at 3.3 V)
- Low Input Capacitance (C_i = 1.5 pF Typ)
- Low Noise Overshoot and Undershoot <10% of V_{CC}
- I_{off} Supports Partial-Power-Down Mode Operation
- Schmitt-Trigger Action Allows Slow Input Transition and Better Switching Noise Immunity at the Input (V_{hvs} = 250 mV Typ at 3.3 V)

Wide Operating V_{CC} Range of 0.8 V to 3.6 V

- Optimized for 3.3-V Operation
- 3.6-V I/O Tolerant to Support Mixed-Mode Signal Operation
- $t_{nd} = 5.9 \text{ ns Max at } 3.3 \text{ V}$
- Suitable for Point-to-Point Applications
- Latch-Up Performance Exceeds 100 mA Per JESD 78. Class II
- ESD Performance Tested Per JESD 22
 - 2000-V Human-Body Model (A114-B, Class II)
 - 1000-V Charged-Device Model (C101)

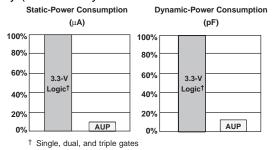




See mechanical drawings for dimensions.

DESCRIPTION/ORDERING INFORMATION

The AUP family is TI's premier solution to the industry's low-power needs in battery-powered portable applications. This family ensures a very low static- and dynamic-power consumption across the entire V_{CC} range of 0.8 V to 3.6 V, resulting in increased battery life (see Figure 1). This product also maintains excellent signal integrity (see the very low undershoot and overshoot characteristics shown in Figure 2).



Switching Characteristics at 25 MHz†

3.5

2.5

Input
Output

0.5

0.5

0.5

1 0 15 20 25 30 35 40 45

Time – ns

† AUP1G08 data at C_L = 15 pF

Figure 1. AUP - The Lowest-Power Family

Figure 2. Excellent Signal Integrity

A

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



This dual 2-input positive-AND gate performs the Boolean function $Y = A \bullet B$ or $Y = \overline{\overline{A} + \overline{B}}$ in positive logic.

NanoStar™ package technology is a major breakthrough in IC packaging concepts, using the die as the package.

This device is fully specified for partial-power-down applications using I_{off} . The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

ORDERING INFORMATION(1)

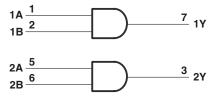
T _A	PACKAGE ⁽²⁾		ORDERABLE PART NUMBER	TOP-SIDE MARKING (3)
	NanoStar™ – WCSP (DSBGA) 0.23-mm Large Bump – YFP	Reel of 3000	SN74AUP2G08YFPR	HE_
–40°C to 85°C	NanoStar™ – WCSP (DSBGA) 0.23-mm Large Bump – YZP (Pb-free)	Reel of 3000	SN74AUP2G08YZPR	HE_
	X2SON - DQE	Reel of 5000	SN74AUP2G08DQER	PR
	QFN - RSE	Reel of 5000	SN74AUP2G08RSER	PR
	VSSOP - DCU	Reel of 3000	SN74AUP2G08DCUR	H08_

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.
- (2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.
- (3) YFP/YZP: The actual top-side marking has three preceding characters to denote year, month, and sequence code, and one following character to designate the wafer fab/assembly site. Pin 1 identifier indicates solder-bump composition (1 = SnPb, = Pb-free). DCU: The actual top-side marking has one additional character to denote wafer fab/assembly site.

FUNCTION TABLE

INP	UTS	OUTPUT
Α	В	Y
L	L	L
L	Н	L
Н	L	L
Н	Н	Н

LOGIC DIAGRAM (POSITIVE LOGIC)



Pin numbers shown are for DCU, YFP, and YZP packages.



ABSOLUTE MAXIMUM RATINGS(1)

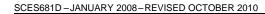
over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	4.6	V
VI	Input voltage range ⁽²⁾		-0.5	4.6	V
Vo	Voltage range applied to any output in the h	nigh-impedance or power-off state (2)	-0.5	4.6	V
Vo	Output voltage range in the high or low stat	e ⁽²⁾	-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V ₁ < 0		-50	mA
I _{OK}	Output clamp current	V _O < 0		-50	mA
Io	Continuous output current		±20	mA	
	Continuous current through V _{CC} or GND			±50	mA
		DCU package		227	
		DQE package		261	
θ_{JA}	Package thermal impedance (3)	RSE package		253	°C/W
		YFP package		98.8	
		YZP package		102	
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

⁽²⁾ The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

⁽³⁾ The package thermal impedance is calculated in accordance with JESD 51-7.





RECOMMENDED OPERATING CONDITIONS(1)

			MIN	MAX	UNIT	
V _{CC}	Supply voltage		0.8	3.6	V	
		$V_{CC} = 0.8 \text{ V}$	V _{CC}			
V	High level input voltage	$V_{CC} = 1.1 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$		V	
V_{IH}	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.6		V	
		$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	2			
		$V_{CC} = 0.8 \text{ V}$		0		
V	Law lavel input valtage	$V_{CC} = 1.1 \text{ V to } 1.95 \text{ V}$		$0.35 \times V_{CC}$	V	
V_{IL}	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	_ v	
		$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		0.9		
VI	Input voltage	·	0	3.6	V	
Vo	Output voltage		0	V _{CC}	V	
		$V_{CC} = 0.8 \text{ V}$		-20	μΑ	
		V _{CC} = 1.1 V		-1.1		
	High lavel autout august	V _{CC} = 1.4 V		-1.7		
I _{OH}	High-level output current	V _{CC} = 1.65		-1.9	mA	
		$V_{CC} = 2.3 \text{ V}$		-3.1		
		$V_{CC} = 3 V$		-4		
		$V_{CC} = 0.8 \text{ V}$		20	μΑ	
		V _{CC} = 1.1 V		1.1		
	Low lovel output outront	$V_{CC} = 1.4 \text{ V}$		1.7		
l _{OL}	Low-level output current	V _{CC} = 1.65 V		1.9	mA	
		$V_{CC} = 2.3 \text{ V}$		3.1		
		V _{CC} = 3 V		4		
Δt/Δν	Input transition rise or fall rate	V _{CC} = 0.8 V to 3.6 V		200	ns/V	
T _A	Operating free-air temperature		-40	85	°C	

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. See the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



ELECTRICAL CHARACTERISTICS

over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST SOMBITIONS	.,	TA	= 25°C	$T_A = -40$ °C t	o 85°C		
PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP MAX	MIN	MAX	UNIT	
	I _{OH} = -20 μA	0.8 V to 3.6 V	V _{CC} - 0.1		V _{CC} - 0.1			
	I _{OH} = -1.1 mA	1.1 V	0.75 × V _{CC}		0.7 × V _{CC}			
	$I_{OH} = -1.7 \text{ mA}$	1.4 V	1.11		1.03			
	I _{OH} = -1.9 mA	1.65 V	1.32		1.3		V	
V _{OH}	I _{OH} = -2.3 mA	221/	2.05		1.97		V	
	$I_{OH} = -3.1 \text{ mA}$	2.3 V	1.9		1.85			
	$I_{OH} = -2.7 \text{ mA}$	3 V	2.72		2.67			
	I _{OH} = -4 mA	3 V	2.6		2.55			
	I _{OL} = 20 μA	0.8 V to 3.6 V		0.1		0.1		
	I _{OL} = 1.1 mA	1.1 V		0.3 × V _{CC}	0	$0.3 \times V_{CC}$		
	I _{OL} = 1.7 mA	1.4 V		0.31		0.37		
\	I _{OL} = 1.9 mA	1.65 V		0.31		0.35	٧	
V _{OL}	I _{OL} = 2.3 mA	221/		0.31		0.33		
	I _{OL} = 3.1 mA	2.3 V		0.44		0.45		
	I _{OL} = 2.7 mA	3 V		0.31		0.33		
	I _{OL} = 4 mA	3 V		0.44		0.45		
A or B input	$V_I = GND \text{ to } 3.6 \text{ V}$	0 V to 3.6 V		0.1		0.5	μΑ	
off	V_{I} or $V_{O} = 0 \text{ V to } 3.6 \text{ V}$	0 V		0.2		0.6	μΑ	
∆I _{off}	V_{I} or $V_{O} = 0 \text{ V to } 3.6 \text{ V}$	0 V to 0.2 V		0.2		0.9	μΑ	
cc	$V_I = GND \text{ or } I_O = 0$ (V_{CC} to 3.6 V)	0.8 V to 3.6 V		0.5		0.9	μА	
ΔI _{CC}	$V_1 = V_{CC} - 0.6 V^{(1)}, I_O = 0$	3.3 V		40		50	μΑ	
	V V or CND	0 V		2			~F	
C _i	$V_I = V_{CC}$ or GND	3.6 V		2			pF	
C _o	V _O = GND	0 V		3			pF	

⁽¹⁾ One input at V_{CC} – 0.6 V, other input at V_{CC} or GND



SWITCHING CHARACTERISTICS

over recommended operating free-air temperature range, C₁ = 5 pF (unless otherwise noted) (see Figure 3 and Figure 4)

FROM TO		то	V _{cc}	$T_A = 25^{\circ}C$			$T_A = -40$ °C to 85°C		LINUT
PARAMETER	(INPUT) (OUTPUT)	MIN		TYP	MAX	MIN	MAX	UNIT	
	A or B Y		0.8 V		19.8				
			1.2 V ± 0.1 V	0.5	7.8	18.8	0.5	19.8	
		V	1.5 V ± 0.1 V	0.5	5.4	11.8	0.5	13.9	
t _{pd}		Y	1.8 V ± 0.15 V	0.5	4.3	9	0.5	11.1	ns
			2.5 V ± 0.2 V	0.5	3	5.7	0.5	7.8	
			3.3 V ± 0.3 V	0.5	2.4	4.6	0.5	5.9	

SWITCHING CHARACTERISTICS

over recommended operating free-air temperature range, C_L = 10 pF (unless otherwise noted) (see Figure 3 and Figure 4)

PARAMETER	FROM	то	V	T,	λ = 25°C		T _A = -40°C t	o 85°C	UNIT
PARAMETER	(INPUT)	(OUTPUT)	V _{CC}	MIN	TYP	MAX	MIN	MAX	UNIT
			0.8 V		23.1				
			1.2 V ± 0.1 V	0.5	8.9	21.1	0.5	22	
	A or B	V	1.5 V ± 0.1 V	0.8	6.3	13.2	0.5	15.1	no
t _{pd}	AUID	T	1.8 V ± 0.15 V	0.6	5	10.1	0.5	12.2	ns
			2.5 V ± 0.2 V	0.5	3.6	7.4	0.5	9	
			3.3 V ± 0.3 V	0.5	2.9	5.1	0.5	6.5	



SWITCHING CHARACTERISTICS

over recommended operating free-air temperature range, C_L = 15 pF (unless otherwise noted) (see Figure 3 and Figure 4)

DADAMETED	FROM	то		T,	_λ = 25°C	;	T _A = -40°C t	o 85°C	LINUT
PARAMETER	(INPUT)	(OUTPUT)	V _{CC}	MIN	TYP	MAX	MIN	MAX	UNIT
			0.8 V		24.7				
			$1.2 \text{ V} \pm 0.1 \text{ V}$	0.5	9.8	21.7	0.5	22.7	7
4	A D	_	1.5 V ± 0.1 V	1.3	4.6	14	0.5	15.7	
t _{pd}	A or B	Ť	1.8 V ± 0.15 V	1.2	5.5	10.6	0.5	12.6	ns
			$2.5 \text{ V} \pm 0.2 \text{ V}$	0.7	4	7	0.5	8.9	
			$3.3 \text{ V} \pm 0.3 \text{ V}$	0.9	3.3	5.5	0.5	6.9	

SWITCHING CHARACTERISTICS

over recommended operating free-air temperature range, C₁ = 30 pF (unless otherwise noted) (see Figure 3 and Figure 4)

PARAMETER	FROM	то	V	T,	₄ = 25°C	:	$T_A = -40$ °C to 85°C		UNIT
PARAMETER	(INPUT)	(OUTPUT)	V _{cc}	MIN	TYP	MAX	MIN	MAX	UNIT
			0.8 V		31.8				
		1.2 V ± 0.1 V	0.6	12.6	26.3	0.5	27		
	A or B	Y	1.5 V ± 0.1 V	2.5	9	16.6	0.7	18.3	ns
t _{pd}	AUID		1.8 V ± 0.15 V	2.3	7.3	12.9	0.5	14.8	
			2.5 V ± 0.2 V	2.1	5.4	8.8	0.8	10.5	
			3.3 V ± 0.3 V	2.1	4.5	6.7	0.9	8.2	

OPERATING CHARACTERISTICS

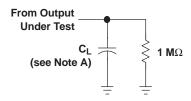
 $T_{\Lambda} = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	V _{CC}	TYP	UNIT
			0.8 V	4	
			1.2 V ± 0.1 V	4	pF
_	Dower discinction conscitones	f = 10 MHz	1.5 V ± 0.1 V	4	
C _{pd}	Power dissipation capacitance	I = IO MHZ	1.8 V ± 0.15 V	4	
			2.5 V ± 0.2 V	4.1	
			3.3 V ± 0.3 V	4.3	

Product Folder Link(s): SN74AUP2G08

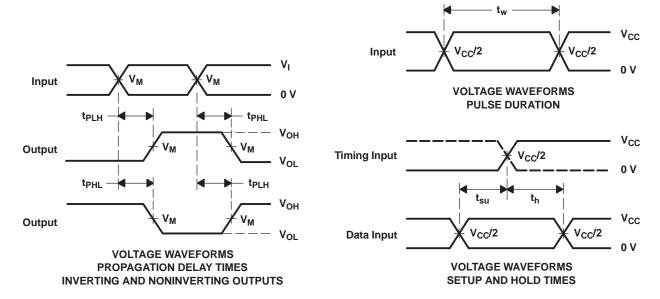


PARAMETER MEASUREMENT INFORMATION (Propagation Delays, Setup and Hold Times, and Pulse Duration)



LOAD CIRCUIT

	V _{CC} = 0.8 V	V _{CC} = 1.2 V ± 0.1 V	V _{CC} = 1.5 V ± 0.1 V	V _{CC} = 1.8 V ± 0.15 V	V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V
C _L	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF
V _M	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2
V _I	V _{CC}	V _{CC}	V _{CC}	V _{CC}	V _{CC}	V _{CC}



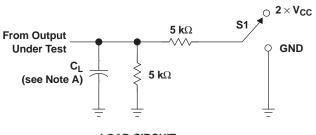
NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50 \Omega$, slew rate \geq 1 V/ns.
- C. The outputs are measured one at a time, with one transition per measurement.
- D. t_{PLH} and t_{PHL} are the same as t_{pd}.
- E. All parameters and waveforms are not applicable to all devices.

Figure 3. Load Circuit and Voltage Waveforms



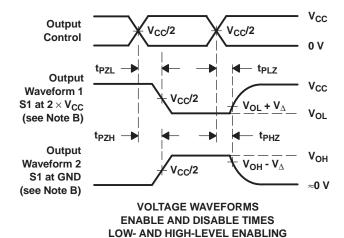
PARAMETER MEASUREMENT INFORMATION (Enable and Disable Times)



TEST	S1
t _{PLZ} /t _{PZL}	2×V _{CC}
t _{PHZ} /t _{PZH}	GND

LOAD CIRCUIT

	V _{CC} = 0.8 V	V _{CC} = 1.2 V ± 0.1 V	V _{CC} = 1.5 V ± 0.1 V	V _{CC} = 1.8 V ± 0.15 V	V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V
C _L V _M V _I V _∆	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF
	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2
	V _{CC}	V _{CC}	V _{CC}	V _{CC}	V _{CC}	V _{CC}
	0.1 V	0.1 V	0.1 V	0.15 V	0.15 V	0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50 \Omega$, slew rate \geq 1 V/ns.
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en}.
- G. All parameters and waveforms are not applicable to all devices.

Figure 4. Load Circuit and Voltage Waveforms

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Product Folder Link(s): SN74AUP2G08



PACKAGE OPTION ADDENDUM

TEXAS INSTRUMENTS

24-Mar-2017

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74AUP2G08DCUR	ACTIVE	VSSOP	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	H08R	Samples
SN74AUP2G08DQER	ACTIVE	X2SON	DQE	8	5000	Green (RoHS & no Sb/Br)	CU NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	PR	Samples
SN74AUP2G08RSER	ACTIVE	UQFN	RSE	8	5000	Green (RoHS & no Sb/Br)	CU NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	PR	Samples
SN74AUP2G08YFPR	ACTIVE	DSBGA	YFP	8	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	HEN	Samples
SN74AUP2G08YZPR	ACTIVE	DSBGA	YZP	8	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	HEN	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.



PACKAGE OPTION ADDENDUM

24-Mar-2017

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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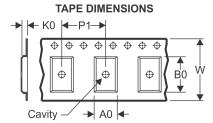
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 3-Aug-2017

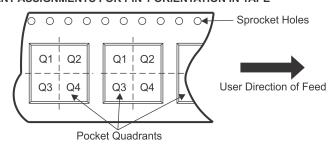
TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AUP2G08DCUR	VSSOP	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74AUP2G08DQER	X2SON	DQE	8	5000	180.0	8.4	1.2	1.6	0.55	4.0	8.0	Q1
SN74AUP2G08RSER	UQFN	RSE	8	5000	180.0	8.4	1.7	1.7	0.7	4.0	8.0	Q2
SN74AUP2G08YFPR	DSBGA	YFP	8	3000	178.0	9.2	0.9	1.75	0.6	4.0	8.0	Q1
SN74AUP2G08YZPR	DSBGA	YZP	8	3000	178.0	9.2	1.02	2.02	0.63	4.0	8.0	Q1

www.ti.com 3-Aug-2017

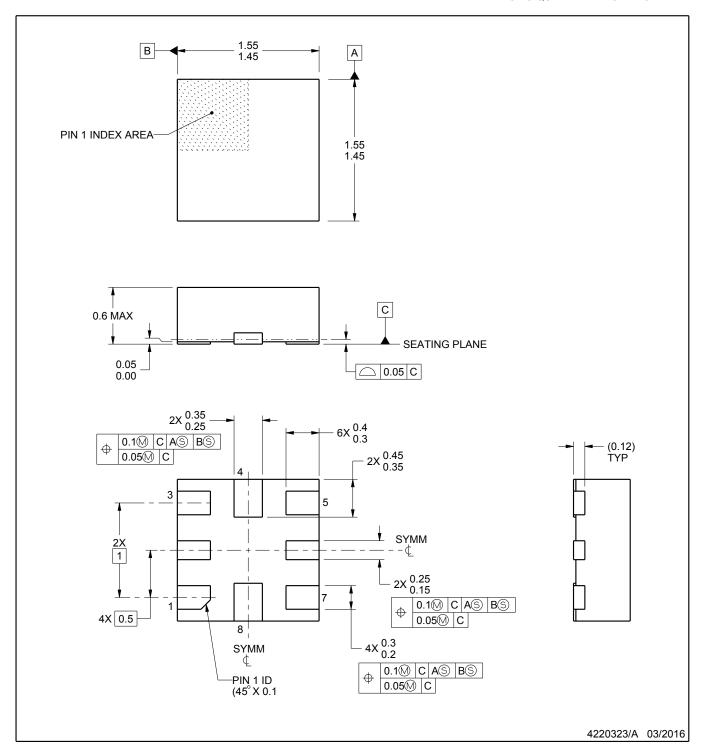


*All dimensions are nominal

7 til dillionsions are nominal								
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
SN74AUP2G08DCUR	VSSOP	DCU	8	3000	202.0	201.0	28.0	
SN74AUP2G08DQER	X2SON	DQE	8	5000	202.0	201.0	28.0	
SN74AUP2G08RSER	UQFN	RSE	8	5000	202.0	201.0	28.0	
SN74AUP2G08YFPR	DSBGA	YFP	8	3000	220.0	220.0	35.0	
SN74AUP2G08YZPR	DSBGA	YZP	8	3000	220.0	220.0	35.0	



PLASTIC QUAD FLATPACK - NO LEAD

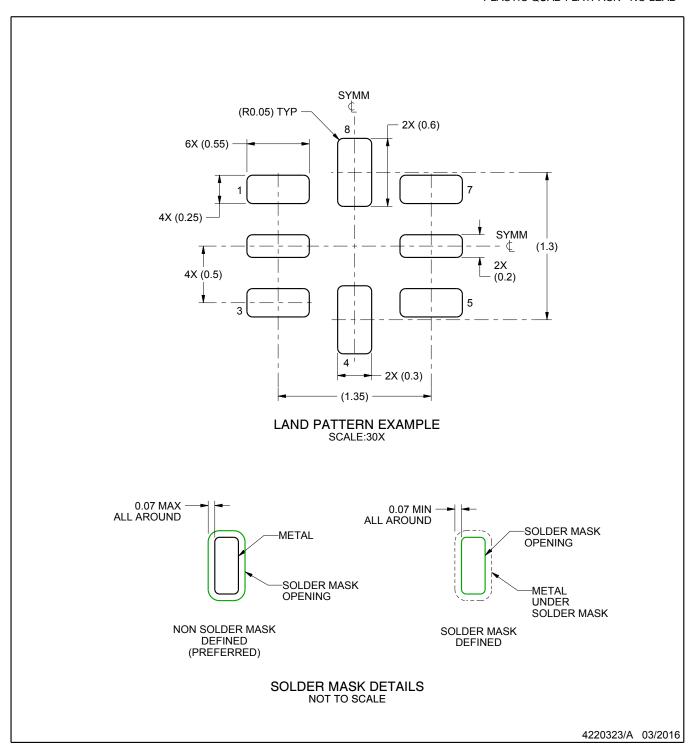


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.



PLASTIC QUAD FLATPACK - NO LEAD

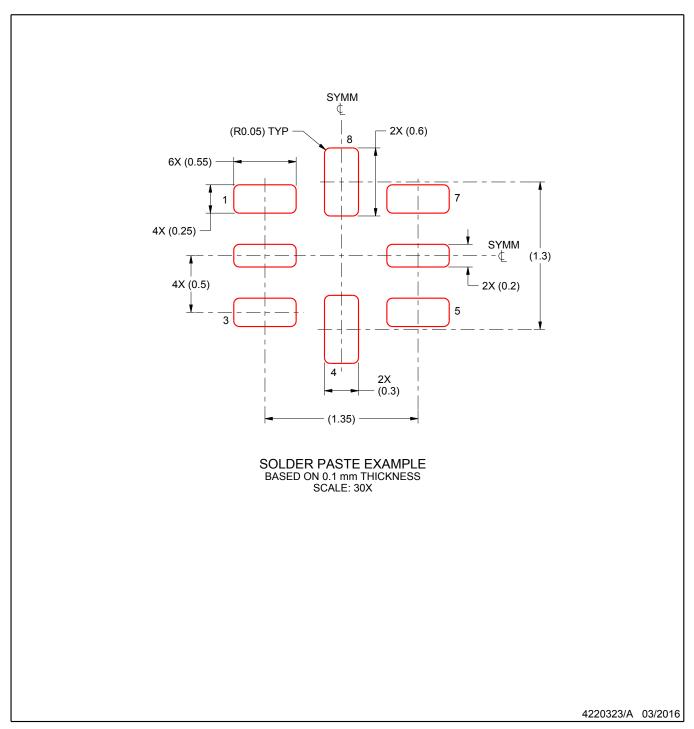


NOTES: (continued)

3. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



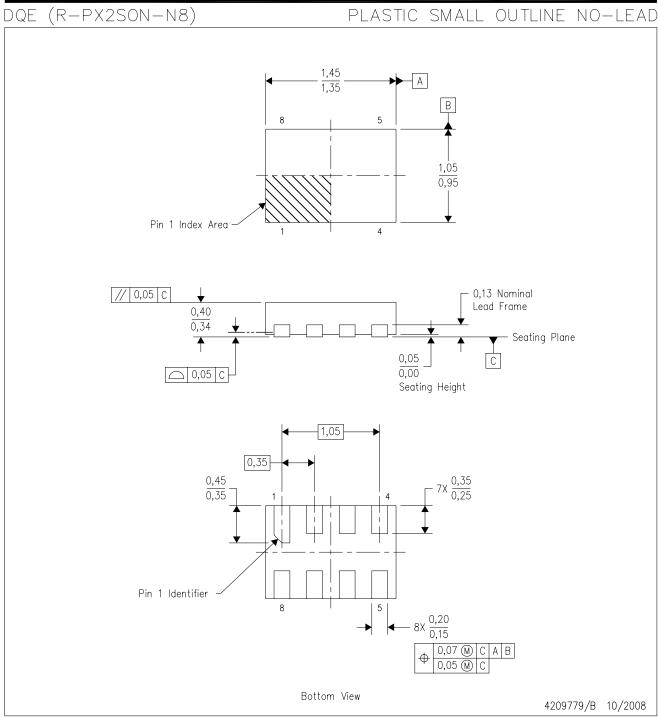
PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





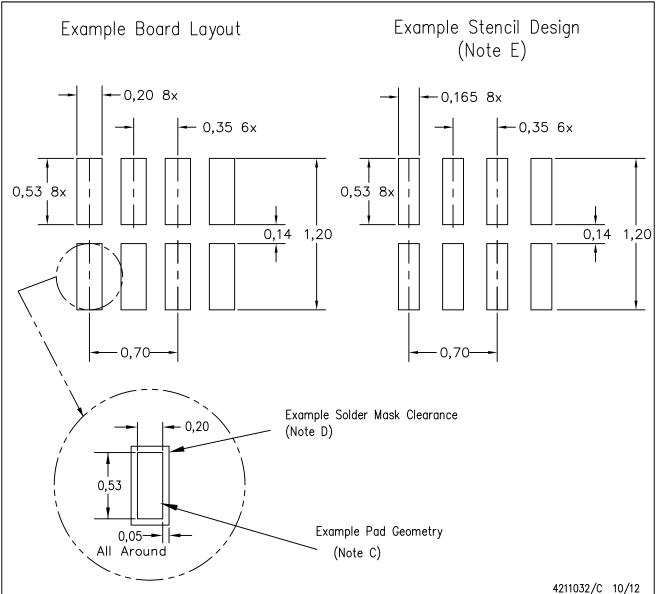
NOTES: All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
 C. SON (Small Outline No-Lead) package configuration.
 D. This package complies to JEDEC MO-287 variation X2EAF.



DQE (R-PX2SON-N8)

PLASTIC SMALL OUTLINE NO-LEAD



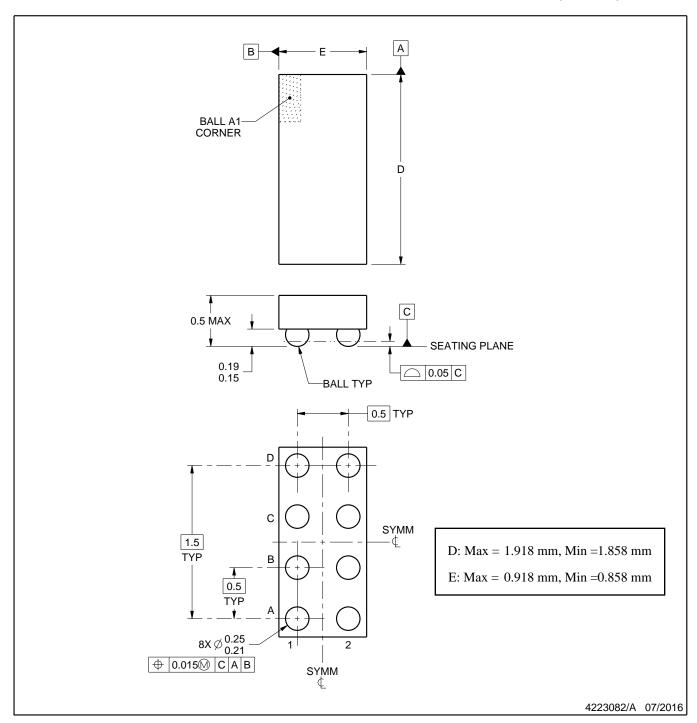
NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads. If 2 mil solder mask is outside PCB vendor capability, it is advised to omit solder mask.
- E. Maximum stencil thickness 0,1016 mm (4 mils). All linear dimensions are in millimeters.
- F. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- G. Over—printing land for acceptable area ratio is not viable due to land width and bridging potential. Customer may further reduce side aperture dimensions if stencil manufacturing process allows for sufficient release at smaller opening.
- H. Suggest stencils cut with lasers such as Fiber Laser that produce the greatest positional accuracy.
- I. Component placement force should be minimized to prevent excessive paste block deformation.





DIE SIZE BALL GRID ARRAY



NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SNVA009 (www.ti.com/lit/snva009).



DIE SIZE BALL GRID ARRAY



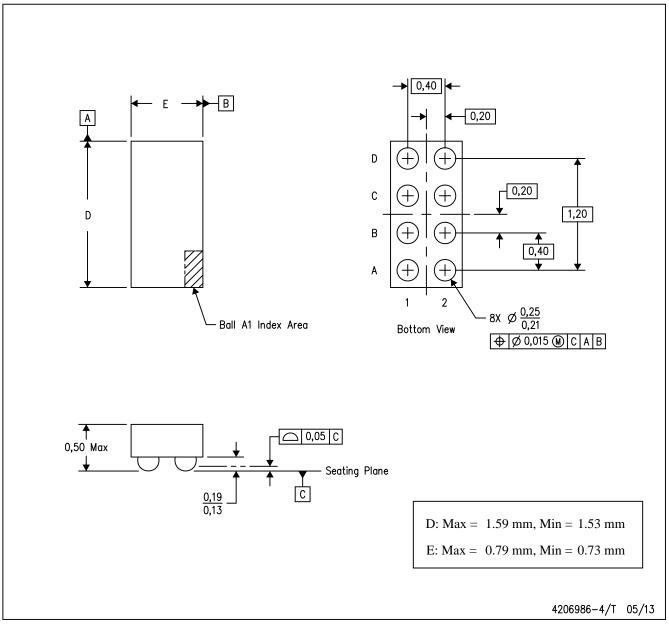
NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



YFP (R-XBGA-N8)

DIE-SIZE BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. NanoFree™ package configuration.

NanoFree is a trademark of Texas Instruments



DCU (R-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE (DIE DOWN)



NOTES:

- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
 - D. Falls within JEDEC MO-187 variation CA.



DCU (S-PDSO-G8)

PLASTIC SMALL OUTLINE PACKAGE (DIE DOWN)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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